

Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,804	CHEN, CHIH-JU
Examiner	Art Unit
Gopal C. Ray	2111

SEARCHED					
Class	Subclass	Date	Examiner		
710	300- 303,62,74, 313,316	8/23/2005	GCR		
711	100,103	8/23/2005	GCR		
361	684,686	8/23/2005	GCR		
361	737	8/23/2005	GCR		
439	59,79,945	8/23/2005	GCR		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	8/22/2005	GCR		
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	8/23/2005	GCR		
EAST: USPT (see search history printouts)	8/22/2005	GCR		
NPL: IEEE Xplore see search history printouts)	8/22/2005	GCR		
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